SPECIFICATION

SPEC. No. C-High-b

D A T E: 2014 June

To

Non-Controlled Copy

CUSTOMER'S PRODUCT NAME

TDK PRODUCT NAME

MULTILAYER CERAMIC CHIP CAPACITORS

C Series / Commercial Grade

High voltage (1000V and over)

Please return this specification to TDK representatives.

If orders are placed without returned specification, please allow us to judge that specification is accepted by your side.

RECEIPT CONFIRMATION

DATE: YEAR MONTH DAY

TDK Corporation Sales Electronic Components Sales & Marketing Group **TDK-EPC** Corporation

Engineering

Ceramic Capacitors Business Group

APPROVED	Person in charge

APPROVED	CHECKED	Person in charge

1. SCOPE

This specification is applicable to chip type multilayer ceramic capacitors with a priority over the other relevant specifications.

Production places defined in this specification shall be TDK-EPC Corporation Japan, TDK (Suzhou) Co., Ltd, and TDK Components U.S.A. Inc.

EXPLANATORY NOTE:

This specification warrants the quality of the ceramic chip capacitors. The chips should be evaluated or confirmed a state of mounted on your product.

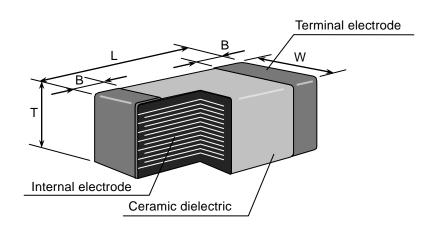
If the use of the chips goes beyond the bounds of the specification, we can not afford to guarantee.

2. CODE CONSTRUCTION

(Example)

Catalog Number : (Web)	<u>C4532</u>	X7R	3D	<u>222</u>	<u>M</u>	130	<u>K</u>	<u>A</u>
	(1)	(2)	(3)	(4)	(5)	(6)	(7)	(8)
Item Description :	<u>C4532</u> (1)	X7R (2)	<u>3D</u> (3)	<u>222</u> (4)	<u>M</u> (5)	<u>T</u> (9)	<u>xxxx</u> (10)	

(1) Type



Please refer to product list for the dimensions of each product.



(2) Temperature Characteristics (Details are shown in table 1 No.7 and No.8 at page 5)

(3) Rated Voltage

Symbol	Rated Voltage
3 A	DC 1 kV
3 D	DC 2 kV
3 F	DC 3 kV

(4) Rated Capacitance

Stated in three digits and in units of pico farads (pF).

The first and Second digits identify the first and second significant figures of the capacitance, the third digit identifies the multiplier.

R is designated for a decimal point.

Example 222 \rightarrow 2,200pF

(5) Capacitance tolerance

Symbol	Tolerance	Capacitance
F	± 1 pF	10pF
K	± 10 %	Over 10pF
M	± 20 %	Over 10pF

(6) Thickness code (Only Catalog Number)

(7) Package code (Only Catalog Number)

(8) Special code (Only Catalog Number)

(9) Packaging

Symbol	Packaging
В	Bulk
Т	Taping

(10) Internal code (Only Item Description)

3. RATED CAPACITANCE AND CAPACITANCE TOLERANCE

3.1 Standard combination of rated capacitance and tolerances

Class	Temperature Characteristics	Capacitano	ce tolerance	Rated capacitance
4	СН	10pF	F (±1pF)	10
ı	C0G	Over 10pF	K (± 10 %)	E – 12 series
2	J B X7R X7S	K (± 10 %) M (± 20 %)		E –3 series

3.2 Capacitance Step in E series

E series		Capacitance Step										
E- 3	1.0			2.2			4.7					
E- 12	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2

4. OPERATING TEMPERATURE RANGE

T.C.	Min. operating Temperature	Max. operating Temperature	Reference Temperature	
C H J B	-25°C	85°C	20°C	
C0G X7R X7S	-55°C	125°C	25°C	

5. STORING CONDITION AND TERM

5 to 40°C at 20 to 70%RH

6 months Max.

6. P.C. BOARD

When mounting on an aluminum substrate, large case sizes such as C4520 and C4532 types are more likely to be affected by heat stress from the substrate. Please inquire separate specification for the large case sizes when mounted on the substrate.

7. INDUSTRIAL WASTE DISPOSAL

Dispose this product as industrial waste in accordance with the Industrial Waste Law.



8. PERFORMANCE

table 1

			table i				
No.	Item	Perfo	rmance	Test or inspection method			
1	External Appearance	No defects which performance.	n may affect	Inspect with magnifying glass (3x)			
2	Insulation Resistance	10,000MΩ min.		Apply 500V DC for 60s.			
3	Voltage Proof	Withstand test voinsulation breakd damage.	•	above DC	ischarge curre	oe applied for 1s.	
4	Capacitance	Within the specif	ied tolerance.	Class	Measuring frequency	Measuring voltage	
				Class1	1MHz±10%	0.5 - 5 Vrms.	
				Class2	1kHz±10%	1.0±0.2 Vrms.	
	Q			Coo No 4 i	n this table for	r magazirina	
5	(Class1)	Rated Capacitance	Q	condition.	n this table for	rmeasuning	
		30pF and over	1,000 min.				
	Under 30pF 400+20xC min. C : Rated capacitance (pF)		400+20×C min.				
			tance (pF)				
6	Dissipation Factor		_	See No.4 i	n this table fo	r measuring	
	(Class2)	T.C.	D.F.	condition.			
		J B X7R X7S	0.03 max.				

(conti	nued)		
No.	Item	Performance	Test or inspection method
7	Temperature Characteristics of Capacitance (Class1)	T.C. Temperature Coeff C H $0 \pm 60 \text{ (ppm/°}$ COG $0 \pm 30 \text{ (ppm/°}$ Capacitance drift within $\pm 0 \pm 0.05 \text{pF}$, whichever larger.	(CH : 20°C) and 85°C temperature. Measuring temperature below 20°C shall be -10°C and -25°C.
8	Temperature Characteristics of Capacitance (Class2)	Capacitance Change No voltage applied JB:±10 X7R:±15 X7S:±22	Capacitance shall be measured by the steps shown in the following table after thermal equilibrium is obtained for each step. AC be calculated ref. STEP3 reading Step Temperature(°C) 1 Reference Temp. ± 2 2 Min. operating Temp. ± 3 Reference Temp. ± 2 4 Max. operating Temp. ± 2
9	Robustness of Terminations	No sign of termination com breakage of ceramic, or oth abnormal signs.	· ·
10	Solderability	New solder to cover over 7 termination. 25% may have pin holes of spots but not concentrated spot. Ceramic surface of A section shall not be exposed due to melting or shifting of terminaterial. A section	solder at 235±5°C for 2±0.5s. Solder: H63A (JIS Z 3282) Flux: Isopropyl alcohol (JIS K 8839) Rosin(JIS K 5902) 25% solid solution.

(continued)

No.	<u>, , , , , , , , , , , , , , , , , , , </u>	em		Perfo	ormance	Test or inspection method											
11	Resistance	External	No cracks are allowed and			Completely soak both terminations in											
	to solder heat	appearance	terminations shall be covered at least 60% with new solder.			solder at 260 ± 5°C for 5±1s.											
		Capacitance	Characteristics Change from the value before test			Preheating condition Temp.: 150 ± 10°C											
			Class 1	C H C0G	Capacitance drift within ± 2.5% or ±0.25pF, whichever larger.	Time: 1 ~ 2min. Flux: Isopropyl alcohol (JIS K 8839) Rosin (JIS K 5902) 25% solid											
			Class 2	J B X7R X7S	± 7.5 %	solution.											
		Q				Solder: H63A (JIS Z 3282)											
		Class1		ated citance	Q	Leave the capacitors in ambient											
			30pF	and over	1,000 min.	condition for 6 to 24h (Class 1) or 24±2h (Class 2) before											
			Unde	er 30pF	400+20×C min.	measurement.											
			C : F	Rated ca	apacitance (pF)												
	-	D.F. Class2	Meet the initial spec.														
		Insulation Resistance	Meet the initial spec.														
		Voltage proof	No insulation breakdown or other damage.														
12	Vibration	External appearance	No mech	nanical d	damage.	Reflow solder the capacitors on a P.C.Board shown in Appendix1											
		Capacitance	Characteristics Change from the value before test			before testing. Vibrate the capacitors with amplitude											
											t.			Class 1	C H C0G	Capacitance drift within ± 2.5% or ±0.25pF, whichever larger.	of 1.5mm P-P changing the frequencies from 10Hz to 55Hz and back to 10Hz in about 1min.
			Class 2	J B X7R X7S	± 7.5 %	Repeat this for 2h each in 3 perpendicular directions.											
		Q															
		(Class1)		ated citance	Q												
					1,000 min.												
			Under 30pF 400+20xC min.														
			C : Rated capacitance (pF)														
		D.F. Class2	Meet the initial spec.														



(continued)

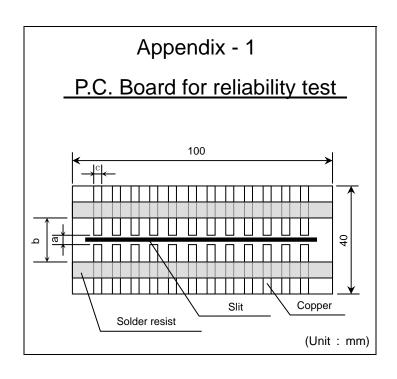
No.	lte	em		Perf	ormance		Test or inspection method					
13	Temperature cycle	External appearance	No mech	anical d	lamage.		Reflow solder the capacitors on a P.C.Board shown in Appendix 1 before					
		Capacitance	value I		Change from the value before te	st	testing. Expose the capacitors in the condition step1 through step 4 and repeat 5					
			Class 1	C H C0G	Capacitance drift within ± 2.5% or ±0.25pF, whiche larger.		times consecutively. Leave the capacitors in ambient					
			Class 2	J B X7R X7S	± 7.5 %			on for 6 to 24h (Cla (Class 2) before m	,			
							Step	Temperature(°C)	Time(min.)			
		Q (Class1)		Rated acitance	Q		1	Min. operating Temp. ± 3 Reference	30 ± 3			
			30pF a	nd over	1,000 min.		2	Temp. ± 2	2 - 5			
			Under	30pF	400+20×C m	in.	3	Max. operating Temp. ± 2 Reference	30 ± 2			
			C : I	Rated ca	apacitance (pF)		4	Temp. ± 2	2 - 5			
		D.F. (Class2)	Meet the	initial s	pec.							
		Insulation Resistance	Meet the initial spec. No insulation breakdown or other damage.									
		Voltage proof				er						
14	Moisture Resistance	External appearance	No mechanical damage.				Reflow solder the capacitors on a P.C.Board shown in Appendix1 before					
	(Steady State)	Steady Capacitance	Charac	teristics	Change from the value before tes		testing	at temperature 40:	13°C 00 to			
						Class 1	C H C0G	Capacitance drift within ± 5% or ± 0.5pF, whicheve larger.	er		H for 500 +24,0h.	£2 C, 90 to
			Class 2	J B X7R X7S	± 12.5 %	<u> </u>	Leave the capacitors in ambient condition for 6 to 24h (Class1) or 24±2h (Class2) before measuremen					
		Q										
		(Class1)		ated citance	Q							
			30pF a	and over	350 min.							
			10pF and o		275+5/2×C IIII	n.						
			C : Rated capacitance (pF)									
		D.F. (Class2)	200% of	initial sp	oec. max.							
		Insulation Resistance	1,000ΜΩ	min.								

(continued)

No.		Item		Perfo	rmance	Test or inspection method
15	Life	External appearance	No mecha	No mechanical damage.		Reflow solder the capacitors on a P.C.Board shown in Appendix 1 before
		Capacitance	Charact	eristics	Change from the value before test	testing.
			Class 1	C H C0G	Capacitance drift within ± 3% or ± 0.3pF, whichever larger.	Apply rated voltage at maximum operating temperature ±2°C for 1,000 +48, 0h.
			Class 2	J B X7R X7S	± 15 %	Charge/discharge current shall not exceed 50mA.
		Q (Class1)	Ra: Capac		Q	Leave the capacitors in ambient condition for 6 to 24h (Class1) or
			30pF ar	30pF and over 350 min. 24±2h (Clas		24±2h (Class2) before measurement.
			10pF ar		275+5/2×C min.	Voltage conditioning (only for class 2)
			C : Rated	d capaci	tance (pF)	Voltage treat the capacitors under
		D.F. (Class2)	200% of i	nitial sp	ec. max.	testing temperature and voltage for 1 hour.
		Insulation Resistance	1,000MΩ min.			Leave the capacitors in ambient condition for 24±2h before measurement. Use this measurement for initial value

^{*}As for the initial measurement of capacitors (Class2) on number 8,11,12, 13 and 14, leave capacitors at 150 -10,0°C for 1 hour and measure the value after leaving capacitors for 24±2h in ambient condition.





Material: Glass Epoxy (As per JIS C6484 GE4)

P.C. Board thickness: 1.6mm

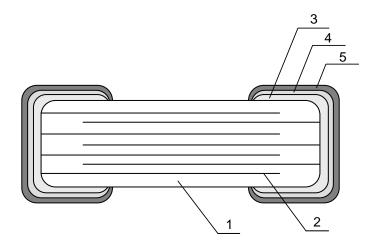
Copper (thickness 0.035mm)

Solder resist

TDK (EIA style)	Dimensions (mm)			
	а	b	С	
C3216 (CC1206)	2.2	5.0	2.0	
C3225 (CC1210)	2.2	5.0	2.9	
C4520 (CC1808)	3.5	7.0	2.5	
C4532 (CC1812)	3.5	7.0	3.7	
C5750 (CC2220)	4.5	8.0	5.6	



9. INSIDE STRUCTURE AND MATERIAL



No.	NAME	MATERIAL			
NO.	INAIVIE	Class1	Class2		
1	Dielectric	CaZrO ₃	BaTiO ₃		
2	Electrode	Nickel (Ni)			
3		Copper (Cu)			
4	Termination	Nickel (Ni)			
5		Tin (Sn)			

10. RECOMMENDATION

It is recommended to provide a slit (about 1mm wide) in the board under the components to improve washing Flux. And please make sure to dry detergent up completely before.

11. SOLDERING CONDITION

Reflow soldering only.



12. Caution

	Caution						
No.	Process	Condition					
1	Operating Condition (Storage,	1-1. Storage1) The capacitors must be stored in an ambient temperature of 5 to 40°C with a relative humidity of 20 to 70%RH. The products should be used within 6 months upon receipt.					
	Transportation) 2) The capacitors must be operated and stored in an environment free condensation and these gases such as Hydrogen Sulphide, Hydrog Chlorine, Ammonia and sulfur.						
		3) Avoid storing in sun light and falling of dew.					
		4) Do not use capacitors under high humidity and high and low atmospheric pressure which may affect capacitors reliability.					
		5) Capacitors should be tested for the solderability when they are stored for long time.					
		1-2. Handling in transportation					
		In case of the transportation of the capacitors, the performance of the capacitors may be deteriorated depending on the transportation condition. (Refer to JEITA RCR-2335B 9.2 Handling in transportation)					
2	 2-1. Operating temperature						
		2) Surface temperature including self heating should be below maximum operating					
	temperature. (Due to dielectric loss, capacitors will heat itself when AC is applied. Especially at high frequencies around its SRF, the heat might be so extreme that it may damage itself or the product mounted on. Please design the circuit so that the maximum temperature of the capacitors including the self heating to be below the maximum allowable operating temperature. Temperature rise at capacitor surface shall be below 20°C)						
	 3) The electrical characteristics of the capacitors will vary depending of temperature. The capacitors should be selected and designed in tatemperature into consideration. 2-2. Operating voltage 1) Operating voltage across the terminals should be below the rated when AC and DC are super imposed, V_{0-P} must be below the rated 						
		AC or pulse with overshooting, V _{P-P} must be below the rated voltage.					
		When the voltage is started to apply to the circuit or it is stopped applying, the irregular voltage may be generated for a transit period because of resonance or switching. Be sure to use the capacitors within rated voltage containing these Irregular voltage.					
		Voltage (1) DC voltage (2) DC+AC voltage (3) AC voltage					
		Positional Measurement (Rated voltage) 0 V _{0-P} 0 V _{P-P} 0					
		Voltage (4) Pulse voltage (A) (5) Pulse voltage (B)					
		Positional Measurement (Rated voltage)					



No.	Process			Condition		
2	Circuit design A Caution	2) Even below the rated voltage, if repetitive high frequency AC or pulse is applied, the reliability of the capacitors may be reduced.				
	_			depending on applie and designed in taki	ed DC and AC voltages. ng the voltages into	
		-	, ,	used in AC and/or ps and generate audil	_	
3	Designing	The amount of sold	er at the termination	ns has a direct effect	on the reliability of the	
J	P.C.board	capacitors. 1) The greater the and the more like	amount of solder, the	he higher the stress	on the chip capacitors, P.C.board, determine the	
			nmon solder land fo each terminations.	r multiple terminatio	ns and provide individual	
		3) Size and recom	mended land dimer	nsions.		
			_	\rightarrow D		
			C	A		
				(mm)		
		Type Symbol	C3216	C3225		
		A	2.0 - 2.4	2.0 – 2.4		
		B	1.0 – 1.2	1.0 – 1.2		
		C	1.1 – 1.6	1.9 – 2.5		
		D	1.0 – 1.3	1.0 – 1.3	•	
		Type Symbol	C4520	C4532	C5750	
		A	3.1 - 3.7	3.1 - 3.7	4.1 – 4.8	
		B	1.2 - 1.4	1.2 - 1.4	1.2 – 1.4	
		C	1.5 - 2.0	2.4 - 3.2	4.0 – 5.0	
		D	1.0 - 1.3	1.0 - 1.3	1.0 – 1.3	
		components to completely before It is recommend	improve washing flore.	ux. And please makated flux (Chlorine o	th) in the board under the sure to dry detergent uncontent: less than 0.1wt%	

	D		Condition			
No. 3	Process Designing P.C.board	5) Recommended	5) Recommended chip capacitors layout is as following.			
	1.0.50010		Disadvantage against bending stress	Advantage against bending stress		
		Mounting face	Perforation or slit	Perforation or slit		
			Break P.C.board with mounted side up.	Break P.C.board with mounted side down.		
		Chip arrangement (Direction)	Mount perpendicularly to perforation or slit Perforation or slit	Mount in parallel with perforation or slit Perforation or slit		
		Distance from slit	Closer to slit is higher stress $(\ell_1 < \ell_2)$	Away from slit is less stress $ \frac{\ell_2}{(\ell_1 < \ell_2)} $		

No. | Process | Condition |

3 | Designing | P.C.board |

Perforation | Perforation | Perforation |

The stress in capacitors is in the following order. |

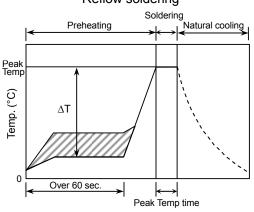
A > B = C > D > E

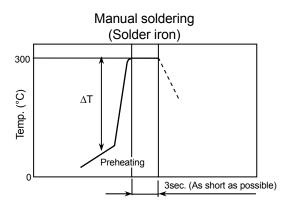
7) Layout recommendation

Example	Use of common solder land	Soldering with chassis	Use of common solder land with other SMD
Need to avoid	Lead wire chip Solder PCB Adhesive Solder land	Chassis Excessive solder	Solder land Excessive solder Missing solder Solder land
Recommen- dation	Solder resist	Solder resist ℓ^2 $\ell^2 > \ell^1$	Solder resist

No.	Process	 Condition 4-1. Stress from mounting head If the mounting head is adjusted too low, it may induce excessive stress in the chip capacitors to result in cracking. Please take following precautions. 1) Adjust the bottom dead center of the mounting head to reach on the P.C.board surface and not press it. 2) Adjust the mounting head pressure to be 1 to 3N of static weight. 3) To minimize the impact energy from mounting head, it is important to provide support from the bottom side of the P.C.board. See following examples. 				
4	Mounting					
			Not recommended	Recommended		
		Single sided mounting	Crack	Support pin		
		Double-sides mounting	Solder peeling Crack	Support pin		
		to cause crack. P	ng jaw is worn out, it may give me lease control the close up dimens preventive maintenance and repla	ion of the centering jaw and		

No.	Process	Condition			
5	Soldering	5-1. Flux selection Although highly-activated flux gives better solderability, substances which increase activity may also degrade the insulation of the chip capacitors. To avoid such degradation, it is recommended following.			
		 It is recommended to use a mildly activated rosin flux (less than 0.1wt% chlorine). Strong flux is not recommended. 			
		2) Excessive flux must be avoided. Please provide proper amount of flux.			
		3) When water-soluble flux is used, enough washing is necessary.			
		5-2. Recommended soldering profile by various methods			
		Reflow soldering			
		Soldering Preheating Natural cooling → ← → ← → ← → ← → ← → ← → ← → ← → ← →			





5-3. Recommended soldering peak temp and peak temp duration

Temp./Duration	Reflow soldering		
Solder	Peak temp(°C)	Duration(sec.)	
Sn-Pb Solder	230 max.	20 max.	
Lead Free Solder	260 max.	10 max.	

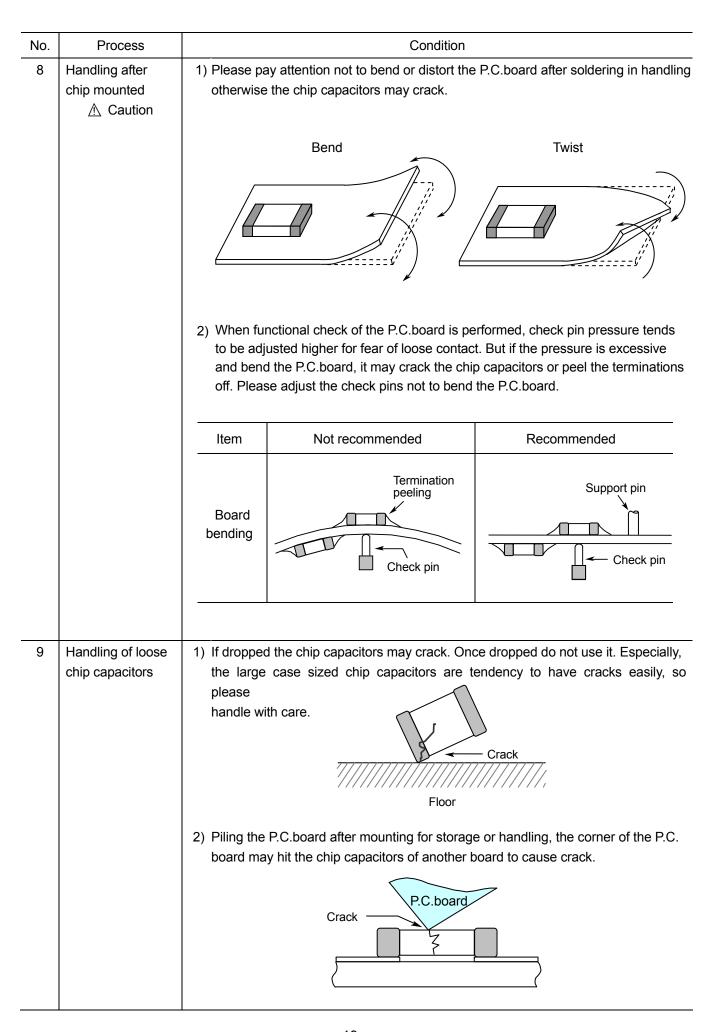
Recommended solder compositions Sn-37Pb (Sn-Pb solder) Sn-3.0Ag-0.5Cu (Lead Free Solder)



No.	Process	Condition					
5	Soldering	5-4. Avoiding thermal shock	(
		1) Preheating condition					
		Soldering	Туре	Ten	np. (°C)		
		Defloured desire	C3216	ΔΤ	≤ 150		
		Reflow soldering	C3225, C4520 C4532, C5750	ΔΤ	í ≤ 130		
		Manual caldering	C3216	ΔΤ	² ≤ 150		
		Manual soldering	C3225, C4520 C4532, C5750	ΔΤ	¹ ≤ 130		
	5-8	cleaning, the temperature 5-5. Amount of solder Excessive solder we temperature change	ire difference (ΔT vill induce highe s and it may resu) must be less that r tensile force in alt in chip cracking	dipped into a solvent for in 100°C. In chip capacitors when g. In sufficient solder may		
		detach the capacitor	s from the P.C.bo	ard.			
		Excessive solder			her tensile force in capacitors to cause ck		
		Adequate		Maximun	n amount amount		
		Insufficient solder		cau chir	v robustness may use contact failure or capacitors come off P.C.board.		
		5-6. Solder repair by solder 1) Selection of the solderin Tip temperature of sold land size. The higher the heat shock may cause Please make sure the time in accordance with chip capacitors with the Recommended solder Temp. (°C)	ng iron tip der iron varies by the tip temperature a crack in the ch tip temp. before s th following recome e condition in 5-4	e, the quicker the ip capacitors. coldering and keep mended condition to avoid the them	operation. However, o the peak temp and n. (Please preheat the nal shock.)		

No.	Process	Condition
5	Soldering	Direct contact of the soldering iron with ceramic dielectric of chip capacitors may cause crack. Do not touch the ceramic dielectric and the terminations by solder iron.
		5-7. Sn-Zn solder Sn-Zn solder affects product reliability. Please contact TDK in advance when utilize Sn-Zn solder.
		5-8. Countermeasure for tombstone The misalignment between the mounted positions of the capacitors and the land patterns should be minimized. The tombstone phenomenon may occur especially the capacitors are mounted (in longitudinal direction) in the same direction of the reflow soldering. (Refer to JEITA RCR-2335B Annex 1 (Informative) Recommendations to prevent the tombstone phenomenon)
6	Cleaning	If an unsuitable cleaning fluid is used, flux residue or some foreign articles may stick to chip capacitors surface to deteriorate especially the insulation resistance.
		2) If cleaning condition is not suitable, it may damage the chip capacitors.
		2)-1. Insufficient washing (1) Terminal electrodes may corrode by Halogen in the flux.
		(2) Halogen in the flux may adhere on the surface of capacitors, and lower the insulation resistance.
		(3) Water soluble flux has higher tendency to have above mentioned problems (1) and (2).
		2)-2. Excessive washing
		When ultrasonic cleaning is used, excessively high ultrasonic energy output can affect the connection between the ceramic chip capacitor's body and the terminal electrode. To avoid this, following is the recommended condition.
		Power: 20 W/ & max. Frequency: 40 kHz max. Washing time: 5 minutes max.
		2)-3. If the cleaning fluid is contaminated, density of Halogen increases, and it may bring the same result as insufficient cleaning.
7	Coating and molding of the	When the P.C.board is coated, please verify the quality influence on the product.
	P.C.board	Please verify carefully that there is no harmful decomposing or reaction gas emission during curing which may damage the chip capacitors.
		Please verify the curing temperature.





No.	Process	Condition
10	Capacitance aging	The capacitors (Class 2) have aging in the capacitance. They may not be used in precision time constant circuit. In case of the time constant circuit, the evaluation should be done well.
11	Estimated life and estimated failure rate of capacitors	As per the estimated life and the estimated failure rate depend on the temperature and the voltage. This can be calculated by the equation described in JEITA RCR-2335B Annex 6 (Informative) Calculation of the estimated lifetime and the estimated failure rate (Voltage acceleration coefficient: 3 multiplication rule, Temperature acceleration coefficient: 10°C rule) The failure rate can be decreased by reducing the temperature and the voltage but they will not be guaranteed.
12	Others A Caution	The products listed on this specification sheet are intended for use in general electronic equipment (AV equipment, telecommunications equipment, home appliances, amusement equipment, computer equipment, personal equipment, office equipment, measurement equipment, industrial robots) under a normal operation and use condition. The products are not designed or warranted to meet the requirements of the applications listed below, whose performance and/or quality require a more stringent level of safety or reliability, or whose failure, malfunction or trouble could cause serious damage to society, person or property. Please understand that we are not responsible for any damage or liability caused by use of the products in any of the applications below or for any other use exceeding the range or conditions set forth in this specification sheet. If you intend to use the products in the applications listed below or if you have special requirements exceeding the range or conditions set forth in this specification, please contact us. (1) Aerospace/Aviation equipment (2) Transportation equipment (cars, electric trains, ships, etc.) (3) Medical equipment (4) Power-generation control equipment (5) Atomic energy-related equipment (6) Seabed equipment (7) Transportation control equipment (8) Public information-processing equipment (9) Military equipment (10) Electric heating apparatus, burning equipment (11) Disaster prevention/crime prevention equipment (12) Safety equipment (13) Other applications that are not considered general-purpose applications, you are
		kindly requested to take into consideration securing protection circuit/device or providing backup circuits in your equipment.



13. Packaging label

Packaging shall be done to protect the components from the damage during transportation and storing, and a label which has the following information shall be attached.

- 1) Inspection No.
- 2) TDK P/N
- 3) Customer's P/N
- 4) Quantity

*Composition of Inspection No.

Example
$$\underline{M}$$
 $\underline{2}$ \underline{A} - \underline{OO} - \underline{OOO} (a) (b) (c) (d) (e)

- a) Line code
- b) Last digit of the year
- c) Month and A for January and B for February and so on. (Skip I)
- d) Inspection Date of the month.
- e) Serial No. of the day

14. Bulk packaging quantity

Total number of components in a plastic bag for bulk packaging: 1,000pcs.

15. TAPE PACKAGING SPECIFICATION

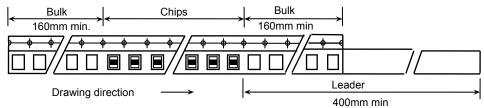
1. CONSTRUCTION AND DIMENSION OF TAPING

1-1. Dimensions of carrier tape

Dimensions of paper tape shall be according to Appendix 2.

Dimensions of plastic tape shall be according to Appendix 3,4.

1-2. Bulk part and leader of taping

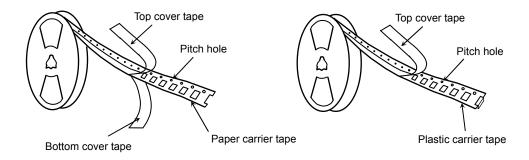


1-3. Dimensions of reel

Dimensions of Ø178 reel shall be according to Appendix 5,6.

Dimensions of Ø330 reel shall be according to Appendix 7,8.

1-4. Structure of taping

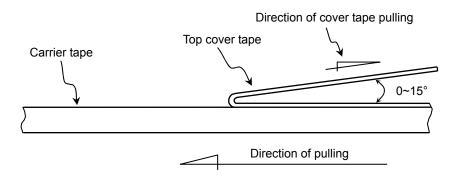


2. CHIP QUANTITY

Туре	Thickness	Taping	Chip quantity(pcs.)	Chip quantity(pcs.)	
туре	of chip	Material	φ178mm reel	φ330mm reel	
C3216	0.85 mm	paper	4,000	10,000	
03210	1.30 mm	plastic	2,000	10,000	
	1.60 mm		2,000	8,000	
C3225	2.00 mm	plastic	1,000	5,000	
	2.50 mm		1,000	3,000	
	0.85 mm				
C4520	1.10 mm		1,000	5,000	
	1.30 mm	plastic			
	1.60 mm			3,000	
	2.00 mm			3,000	
	1.30 mm			5,000	
	1.60 mm		1,000		
C4532	2.00 mm	plastic		3,000	
	2.30 mm		500	3,000	
	2.50 mm		300		
	1.60 mm		1,000		
C5750	2.00 mm	plastic	500	3,000	
	2.50 mm		500		

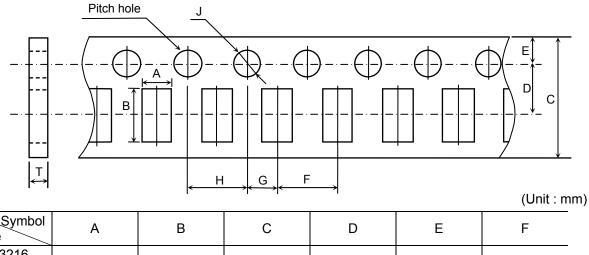
3. PERFORMANCE SPECIFICATIONS

3-1. Fixing peeling strength (top tape) 0.05-0.7N. (See the following figure.)



- 3-2. Carrier tape shall be flexible enough to be wound around a minimum radius of 30mm with components in tape.
- 3-3. The missing of components shall be less than 0.1%
- 3-4. Components shall not stick to fixing tape.
- 3-5. The fixing tapes shall not protrude beyond the edges of the carrier tape not shall cover the sprocket holes.

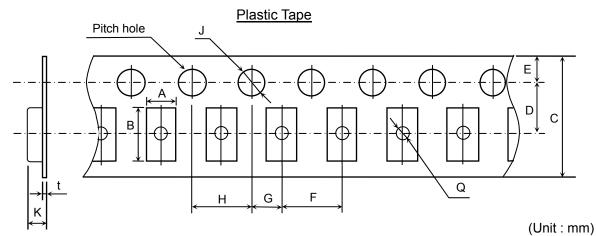
Paper Tape



Type	Α	В	С	D	E	F
C3216 (CC1206)	(1.90)	(3.50)	8.00 ± 0.30	3.50 ± 0.05	1.75 ± 0.10	4.00 ± 0.10
Symbol Type	G	Н	J	Т		
C3216 (CC1206)	2.00 ± 0.05	4.00 ± 0.10	Ø 1.5 +0.10 0	1.10 max.		

^{*} The values in the parentheses () are for reference.

Appendix 3



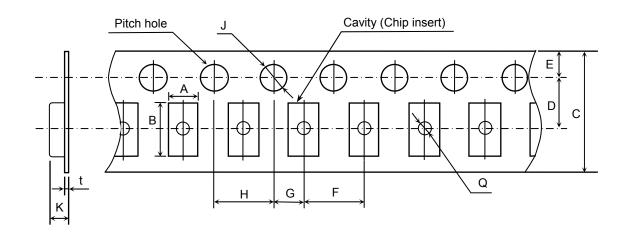
						-
Symbol Type	Α	В	С	D	E	F
C3216 (CC1206)	(1.90)	(3.50)	8.00 ± 0.30	3.50 ± 0.05	1.75 ± 0.10	4.00 ± 0.10
C3225 (CC1210)	(2.90)	(3.60)	$[12.0 \pm 0.30]$	$[5.50 \pm 0.05]$	1.75 ± 0.10	4.00 ± 0.10
Symbol Type	G	Н	J	К	t	Q
C3216 (CC1206)	2.00 ± 0.05	4.00 ± 0.10	Ø 1.5 +0.10	2.50 max.	0.30 max.	Ø 0.50 min.
C3225 (CC1210)	2.00 ± 0.05	4.00 ± 0.10	0 1.5	3.20 max.	0.60 max.	Ø 0.50 mm.

^{*} The values in the parentheses () are for reference.

^{*} As for 2.5mm thickness products, apply values in the brackets [].



Plastic Tape

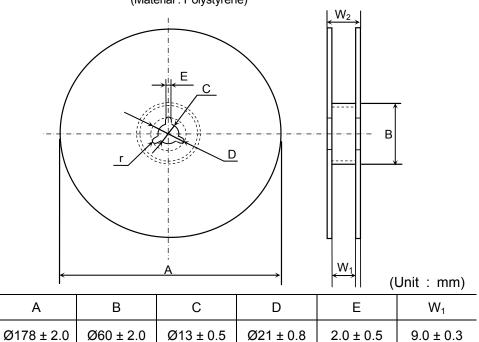


(Unit:mm)

Symbol Type	А	В	С	D	E	F
C4520 (CC1808)	(2.50)	(5.10)				
C4532 (CC1812)	(3.60)	(4.90)	12.0 ± 0.30	5.50 ± 0.05	1.75 ± 0.10	8.00 ± 0.10
C5750 (CC2220)	(5.40)	(6.10)				
	T	T	T	T	T	
Symbol Type	G	Н	J	К	t	Q
C4520 (CC1808)						
C4532 (CC1812)	2.00 ± 0.05	4.00 ± 0.10	Ø 1.5 +0.10	6.50 max.	0.60 max.	Ø 1.50 min.
C5750						

^{*} The values in the parentheses () are for reference.

C3216, C3225 (As for C3225 type, any thickness of the item except 2.5mm) (Material : Polystyrene)



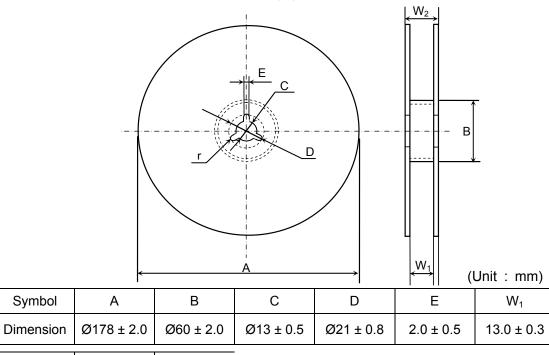
Symbol	W_2	r
Dimension	13.0 ± 1.4	1.0

Symbol

Dimension

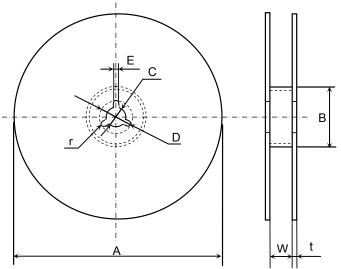
Appendix 6

C3225, C4520, C4532, C5750 (As for C3225 type, applied to 2.5mm thickness products) (Material : Polystyrene)



Symbol	W ₂	r
Dimension	17.0 ± 1.4	1.0

C3216, C3225 (As for C3225 type, any thickness of the item except 2.5mm) $\,$ (Material : Polystyrene)

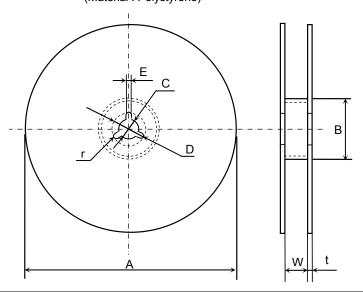


	ľ			→	\longleftrightarrow	(Unit :	mm)
Symbol	Α	В	С	D	Е	W	
Dimension	Ø382 max. (Nominal Ø330)	Ø50 min.	Ø13 ± 0.5	Ø21 ± 0.8	2.0 ± 0.5	10.0 ± 1.5	

Symbol	t	r
Dimension	2.0 ± 0.5	1.0

Appendix 8

C3225, C4520, C4532, C5750 (As for C3225 type, applied to 2.5mm thickness products) (Material : Polystyrene)



(Unit: mm)

Symbol	А	В	С	D	Е	W
Dimension	Ø382 max. (Nominal Ø330)	Ø50 min.	Ø13 ± 0.5	Ø21 ± 0.8	2.0 ± 0.5	14.0 ± 1.5

Symbol	t	r
Dimension	2.0 ± 0.5	1.0